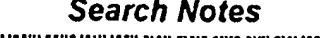


<b>Search Notes</b> 	<b>Application/Control No.</b>  09/744,664	<b>Applicant(s)/Patent under Reexamination</b>  STRATTON ET AL.
	<b>Examiner</b>  Christopher S. Kim	<b>Art Unit</b>  3752

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
CHS1		12/28/05	CCR